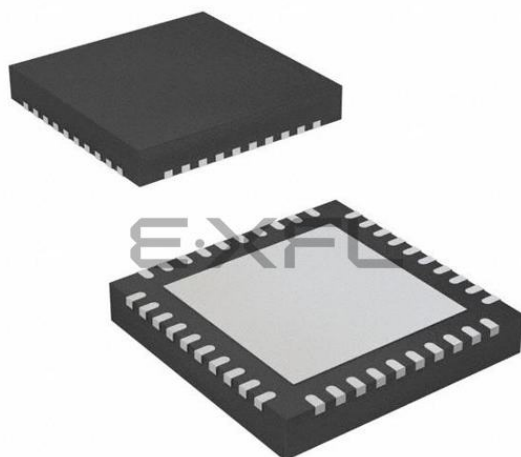




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Details

Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I ² C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, I ² S, POR, PWM, WDT
Number of I/O	27
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	40-VQFN Exposed Pad
Supplier Device Package	PG-VQFN-40-13
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xmc1202q040x0032abxuma1

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1 Summary of Features

The XMC1200 devices are members of the XMC1000 family of microcontrollers based on the ARM Cortex-M0 processor core. The XMC1200 series devices are optimized for LED Lighting and Human-Machine interface (HMI) applications.

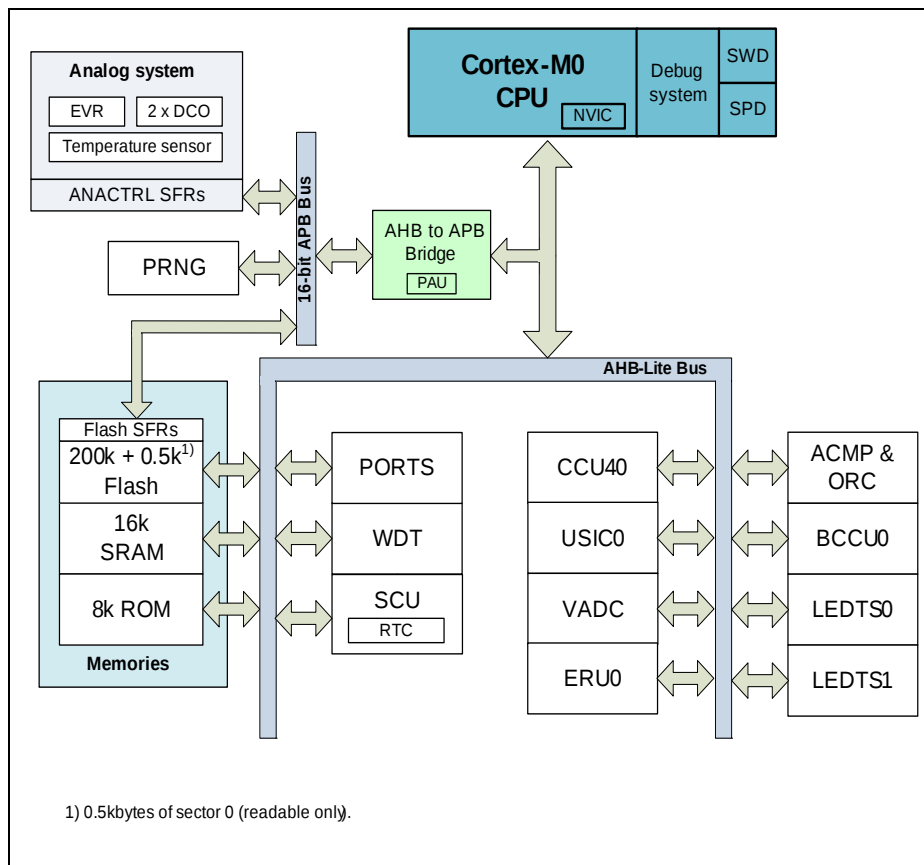


Figure 1 System Block Diagram

CPU Subsystem

- CPU Core
 - High Performance 32-bit ARM Cortex-M0 CPU
 - Most of 16-bit Thumb instruction set
 - Subset of 32-bit Thumb2 instruction set

Summary of Features
Table 1 Synopsis of XMC1200 Device Types (cont'd)

Derivative	Package	Flash Kbytes	SRAM Kbytes
XMC1200-T038F0200	PG-TSSOP-38-9	200	16
XMC1202-T028X0016	PG-TSSOP-28-16	16	16
XMC1202-T028X0032	PG-TSSOP-28-16	32	16
XMC1202-T016X0016	PG-TSSOP-16-8	16	16
XMC1202-T016X0032	PG-TSSOP-16-8	32	16
XMC1202-Q024X0016	PG-VQFN-24-19	16	16
XMC1202-Q024X0032	PG-VQFN-24-19	32	16
XMC1201-Q040F0016	PG-VQFN-40-13	16	16
XMC1201-Q040F0032	PG-VQFN-40-13	32	16
XMC1201-Q040F0064	PG-VQFN-40-13	64	16
XMC1201-Q040F0128	PG-VQFN-40-13	128	16
XMC1201-Q040F0200	PG-VQFN-40-13	200	16
XMC1202-Q040X0016	PG-VQFN-40-13	16	16
XMC1202-Q040X0032	PG-VQFN-40-13	32	16

1.3 Device Type Features

The following table lists the available features per device type.

Table 2 Features of XMC1200 Device Types¹⁾

Derivative	ADC channel	ACMP	BCCU	LEDTS
XMC1200-T038	16	3	1	2
XMC1201-T038	16	-	-	2
XMC1202-T028	14	3	1	-
XMC1202-T016	11	2	1	-
XMC1202-Q024	13	3	1	-
XMC1201-Q040	16	-	-	2
XMC1202-Q040	16	3	1	-

1) Features that are not included in this table are available in all the derivatives

2 General Device Information

This section summarizes the logic symbols and package pin configurations with a detailed list of the functional I/O mapping.

2.1 Logic Symbols

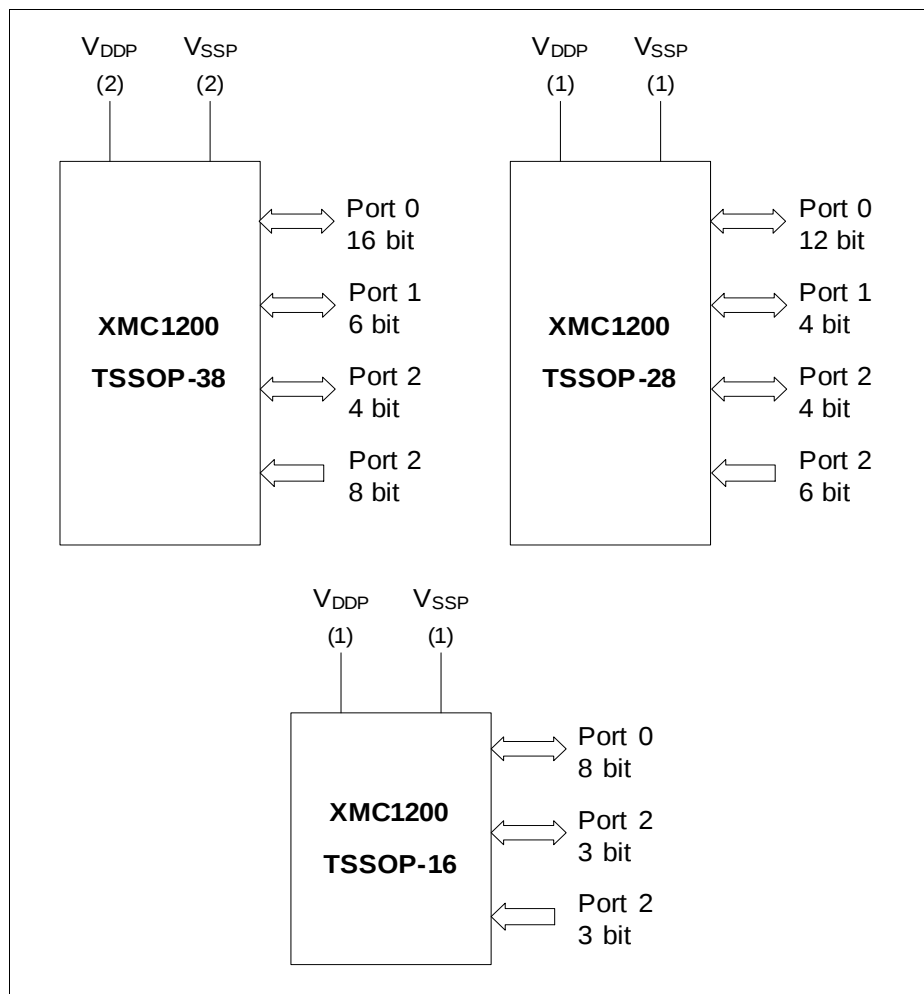


Figure 2 XMC1200 Logic Symbol for TSSOP-38, TSSOP-28 and TSSOP-16

2.2 Pin Configuration and Definition

The following figures summarize all pins, showing their locations on the different packages.

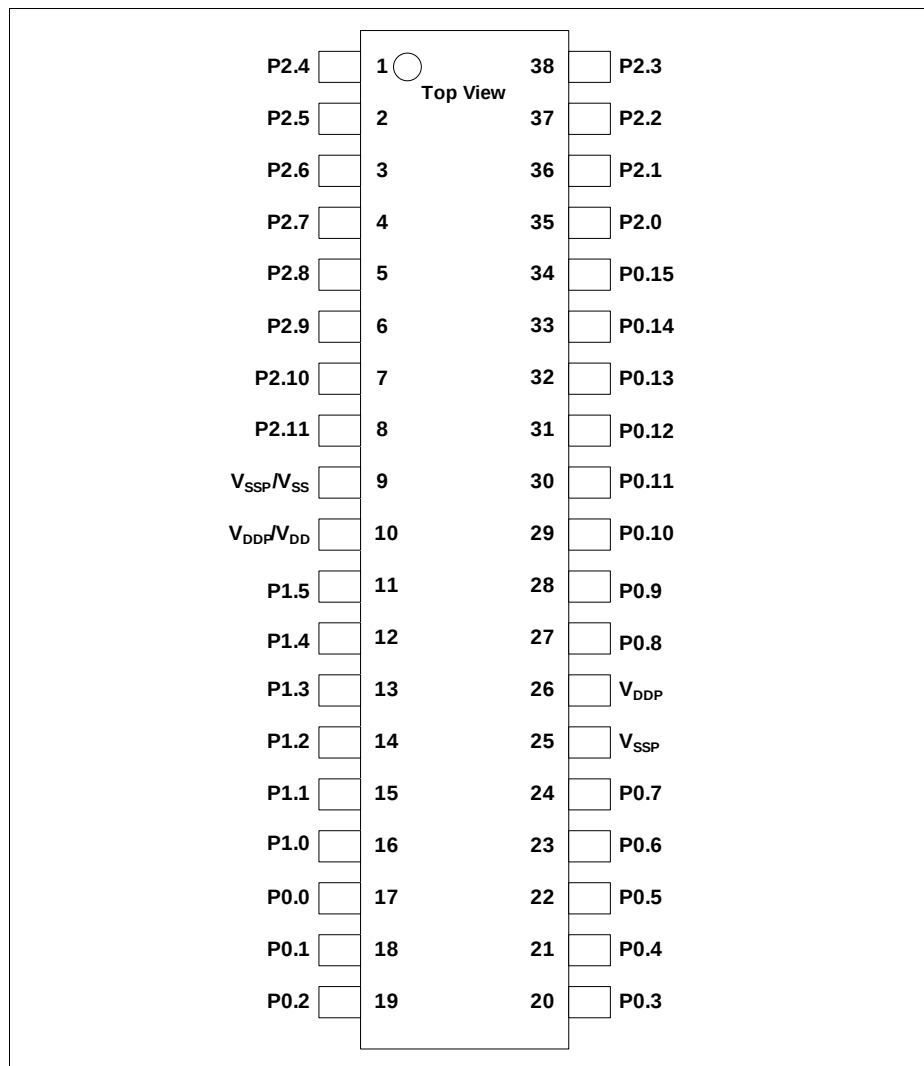


Figure 4 XMC1200 PG-TSSOP-38 Pin Configuration (top view)

2.2.1 Package Pin Summary

The following general building block is used to describe each pin:

Table 5 Package Pin Mapping Description

Function	Package A	Package B	...	Pad Type
Px.y	N	N		Pad Class

The table is sorted by the "Function" column, starting with the regular Port pins (Px.y), followed by the supply pins.

The following columns, titled with the supported package variants, lists the package pin number to which the respective function is mapped in that package.

The "Pad Type" indicates the employed pad type:

- STD_INOUT (standard bi-directional pads)
- STD_INOUT/AN (standard bi-directional pads with analog input)
- High Current (high current bi-directional pads)
- STD_IN/AN (standard input pads with analog input)
- Power (power supply)

Details about the pad properties are defined in the Electrical Parameters.

Table 6 Package Pin Mapping

Function	VQFN 40	TSSOP 38	TSSOP 28	VQFN 24	TSSOP 16	Pad Type	Notes
P0.0	23	17	13	15	7	STD_INOUT	
P0.1	24	18	-	-	-	STD_INOUT	
P0.2	25	19	-	-	-	STD_INOUT	
P0.3	26	20	-	-	-	STD_INOUT	
P0.4	27	21	14	-	-	STD_INOUT	
P0.5	28	22	15	16	8	STD_INOUT	
P0.6	29	23	16	17	9	STD_INOUT	
P0.7	30	24	17	18	10	STD_INOUT	
P0.8	33	27	18	19	11	STD_INOUT	
P0.9	34	28	19	20	12	STD_INOUT	
P0.10	35	29	20	-	-	STD_INOUT	
P0.11	36	30	-	-	-	STD_INOUT	
P0.12	37	31	21	21	-	STD_INOUT	

General Device Information

Table 6 Package Pin Mapping

Function	VQFN 40	TSSOP 38	TSSOP 28	VQFN 24	TSSOP 16	Pad Type	Notes
VDD	14	10	8	10	6	Power	Supply VDD, ADC reference voltage/ORC reference voltage. VDD has to be supplied with the same voltage as VDDP
VDDP	15	10	8	10	6	Power	I/O port supply
VSSP	31	25	-	-	-	Power	I/O port ground
VDDP	32	26	-	-	-	Power	I/O port supply
VSSP	Exp. Pad	-	-	Exp. Pad	-	Power	Exposed Die Pad The exposed die pad is connected internally to VSSP. For proper operation, it is mandatory to connect the exposed pad to the board ground. For thermal aspects, please refer to the Package and Reliability chapter.

2.2.2 Port I/O Functions

The following general building block is used to describe each PORT pin:

Table 7 Port I/O Function Description

Function	Outputs			Inputs		
	ALT1	ALTn	HWO0	HWI0	Input	Input
P0.0		MODA.OUT	MODB.OUT	MODB.INA	MODC.INA	
Pn.y	MODA.OUT				MODA.INA	MODC.INB

Pn.y is the port pin name, defining the control and data bits/registers associated with it. As GPIO, the port is under software control. Its input value is read via Pn_IN.y, Pn_OUT defines the output value.

Up to seven alternate output functions (ALT1/2/3/4/5/6/7) can be mapped to a single port pin, selected by Pn_IOC.R.PC. The output value is directly driven by the respective module, with the pin characteristics controlled by the port registers (within the limits of the connected pad).

The port pin input can be connected to multiple peripherals. Most peripherals have an input multiplexer to select between different possible input sources.

The input path is also active while the pin is configured as output. This allows to feedback an output to on-chip resources without wasting an additional external pin.

By Pn_HWSEL, it is possible to select between different hardware “masters” (HWO0/HWI0, HWO1/HWI1). The selected peripheral can take control of the pin(s). Hardware control overrules settings in the respective port pin registers.

3.1.2 Absolute Maximum Ratings

Stresses above the values listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions may affect device reliability.

Table 9 Absolute Maximum Rating Parameters

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
Junction temperature	T_J	SR	-40	–	115	°C	–
Storage temperature	T_S	SR	-40	–	125	°C	–
Voltage on power supply pin with respect to V_{SSP}	V_{DDP}	SR	-0.3	–	6	V	–
Voltage on any pin with respect to V_{SSP}	V_{IN}	SR	-0.5	–	$V_{DDP} + 0.5$ or max. 6	V	whichever is lower
Voltage on any analog input pin with respect to V_{SSP}	V_{AIN} V_{AREF}	SR	-0.5	–	$V_{DDP} + 0.5$ or max. 6	V	–
Input current on any pin during overload condition	I_{IN}	SR	-10	–	10	mA	–
Absolute sum of all input currents during overload condition	$\Sigma I_{IN} $	SR	–	–	50	mA	–
Analog comparator input voltage	V_{CM}	SR	-0.3	–	$V_{DDP} + 0.3$	V	

3.1.3 Operating Conditions

The following operating conditions must not be exceeded in order to ensure correct operation and reliability of the XMC1200. All parameters specified in the following tables refer to these operating conditions, unless noted otherwise.

Table 10 Operating Conditions Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Ambient Temperature	T_A SR	-40	–	85	°C	Temp. Range F
		-40	–	105	°C	Temp. Range X
Digital supply voltage ¹⁾	V_{DDP} SR	1.8	–	5.5	V	
MCLK Frequency	f_{MCLK} CC	–	–	33.2	MHz	CPU clock
PCLK Frequency	f_{PCLK} CC	–	–	66.4	MHz	Peripherals clock

1) See also the Supply Monitoring thresholds, [Chapter 3.3.3](#).

Electrical Parameter
Table 11 Input/Output Characteristics (Operating Conditions apply) (cont'd)

Parameter	Symbol		Limit Values		Unit	Test Conditions
			Min.	Max.		
Input high voltage on port pins (Large Hysteresis)	V_{IHPL}	SR	$0.85 \times V_{DDP}$	—	V	CMOS Mode (5 V, 3.3 V & 2.2 V) ³⁾
Input Hysteresis ¹⁾	HYS	CC	$0.08 \times V_{DDP}$	—	V	CMOS Mode (5 V), Standard Hysteresis
			$0.03 \times V_{DDP}$	—	V	CMOS Mode (3.3 V), Standard Hysteresis
			$0.02 \times V_{DDP}$	—	V	CMOS Mode (2.2 V), Standard Hysteresis
			$0.5 \times V_{DDP}$	$0.75 \times V_{DDP}$	V	CMOS Mode(5 V), Large Hysteresis
			$0.4 \times V_{DDP}$	$0.75 \times V_{DDP}$	V	CMOS Mode(3.3 V), Large Hysteresis
			$0.2 \times V_{DDP}$	$0.65 \times V_{DDP}$	V	CMOS Mode(2.2 V), Large Hysteresis
Pull-up resistor on port pins	R_{PUP}	CC	20	50	kohm	$V_{IN} = V_{SSP}$
Pull-down resistor on port pins	R_{PDP}	CC	20	50	kohm	$V_{IN} = V_{DDP}$
Input leakage current ²⁾	I_{OZP}	CC	-1	1	μA	$0 < V_{IN} < V_{DDP}$, $T_A \leq 105^\circ\text{C}$
Overload current on any pin	I_{OVP}	SR	-5	5	mA	
Absolute sum of overload currents	$\Sigma I_{OV} $	SR	—	25	mA	³⁾
Voltage on any pin during V_{DDP} power off	V_{PO}	SR	—	0.3	V	⁴⁾
Maximum current per pin (excluding P1, V_{DDP} and V_{SS})	I_{MP}	SR	-10	11	mA	—
Maximum current per high current pins	I_{MP1A}	SR	-10	50	mA	—

Electrical Parameter
Table 12 ADC Characteristics (Operating Conditions apply) (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Gain settings	G_{IN} CC	1			–	GNCTR _{xz} .GAIN _y = 00 _B (unity gain)
		3			–	GNCTR _{xz} .GAIN _y = 01 _B (gain g1)
		6			–	GNCTR _{xz} .GAIN _y = 10 _B (gain g2)
		12			–	GNCTR _{xz} .GAIN _y = 11 _B (gain g3)
Sample Time	t_{sample} CC	3	–	–	1 / f_{ADC}	$V_{DDP} = 5.0$ V
		3	–	–	1 / f_{ADC}	$V_{DDP} = 3.3$ V
		30	–	–	1 / f_{ADC}	$V_{DDP} = 1.8$ V
Sigma delta loop hold time	t_{SD_hold} CC	20	–	–	μs	Residual charge stored in an active sigma delta loop remains available
Conversion time in fast compare mode	t_{CF} CC	9			1 / f_{ADC}	²⁾
Conversion time in 12-bit mode	t_{C12} CC	20			1 / f_{ADC}	²⁾
Maximum sample rate in 12-bit mode ³⁾	f_{C12} CC	–	–	$f_{ADC} / 42.5$	–	1 sample pending
		–	–	$f_{ADC} / 62.5$	–	2 samples pending
Conversion time in 10-bit mode	t_{C10} CC	18			1 / f_{ADC}	²⁾
Maximum sample rate in 10-bit mode ³⁾	f_{C10} CC	–	–	$f_{ADC} / 40.5$	–	1 sample pending
		–	–	$f_{ADC} / 58.5$	–	2 samples pending
Conversion time in 8-bit mode	t_{C8} CC	16			1 / f_{ADC}	²⁾

3.2.4 Analog Comparator Characteristics

Table 14 below shows the Analog Comparator characteristics.

Table 14 Analog Comparator Characteristics (Operating Conditions apply)

Parameter	Symbol		Limit Values			Unit	Notes/ Test Conditions
			Min.	Typ.	Max.		
Input Voltage	V_{CMP}	SR	-0.05	–	$V_{\text{DDP}} + 0.05$	V	
Input Offset	V_{CMPOFF}	CC	–	+/-3	–	mV	High power mode $\Delta V_{\text{CMP}} < 200 \text{ mV}$
			–	+/-20	–	mV	Low power mode ²⁾ $\Delta V_{\text{CMP}} < 200 \text{ mV}$
Propagation Delay ¹⁾²⁾	t_{PDELAY}	CC	–	25	–	ns	High power mode, $\Delta V_{\text{CMP}} = 100 \text{ mV}$
			–	80	–	ns	High power mode, $\Delta V_{\text{CMP}} = 25 \text{ mV}$
			–	250	–	ns	Low power mode, $\Delta V_{\text{CMP}} = 100 \text{ mV}$
			–	700	–	ns	Low power mode, $\Delta V_{\text{CMP}} = 25 \text{ mV}$
Current Consumption ²⁾	I_{ACMP}	CC	–	100	–	μA	First active ACMP in high power mode, $\Delta V_{\text{CMP}} > 30 \text{ mV}$
			–	66	–	μA	Each additional ACMP in high power mode, $\Delta V_{\text{CMP}} > 30 \text{ mV}$
			–	10	–	μA	First active ACMP in low power mode
			–	6	–	μA	Each additional ACMP in low power mode
Input Hysteresis ²⁾	V_{HYS}	CC	–	15	–	mV	
Filter Delay ¹⁾²⁾	t_{FDELAY}	CC	–	5	–	ns	

1) Total Analog Comparator Delay is the sum of Propagation Delay and Filter Delay.

2) Not subject to production test, verified by design.

Electrical Parameter

Table 17 provides the active current consumption of some modules operating at 5 V power supply at 25 °C. The typical values shown are used as a reference guide on the current consumption when these modules are enabled.

Table 17 Typical Active Current Consumption¹⁾

Active Current Consumption	Symbol	Limit Values	Unit	Test Condition
		Typ.		
Baseload current	I_{CPUDDC}	5.04	mA	Modules including Core, SCU, PORT, memories, ANATOP ²⁾
VADC and SHS	I_{ADCDDC}	3.4	mA	Set CGATCLR0.VADC to 1 ³⁾
USIC0	I_{USIC0DDC}	0.87	mA	Set CGATCLR0.USIC0 to 1 ⁴⁾
CCU40	I_{CCU40DDC}	0.94	mA	Set CGATCLR0.CCU40 to 1 ⁵⁾
LEDTSx	I_{LTSxDDC}	0.76	mA	Set CGATCLR0.LEDTSx to 1 ⁶⁾
BCCU0	I_{BCCU0DDC}	0.24	mA	Set CGATCLR0.BCCU0 to 1 ⁷⁾
WDT	I_{WDTDDC}	0.03	mA	Set CGATCLR0.WDT to 1 ⁸⁾
RTC	I_{RTCDDC}	0.01	mA	Set CGATCLR0.RTC to 1 ⁹⁾

1) Not subject to production test, verified by design/characterisation.

2) Baseload current is measured with device running in user mode, MCLK=PCLK=32 MHz, with an endless loop in the flash memory. The clock to the modules stated in CGATSTAT0 are gated.

3) Active current is measured with: module enabled, MCLK=32 MHz, running in auto-scan conversion mode

4) Active current is measured with: module enabled, alternating messages sent to PC at 57.6kbaud every 200ms

5) Active current is measured with: module enabled, MCLK=PCLK=32 MHz, 1 CCU4 slice for PWM switching from 1500Hz and 1000Hz at regular intervals, 1 CCU4 slice in capture mode for reading period and duty cycle

6) Active current is measured with: module enabled, MCLK=32 MHz, 1 LED column, 6 LED/TS lines, Pad Scheme A with large pad hysteresis config, time slice duration = 1.048 ms

7) Active current is measured with: module enabled, MCLK=32 MHz, PCLK=64MHz, FCLK=0.8MHz, Normal mode (BCCU Clk = FCLK/4), 3 BCCU Channels and 1 Dimming Engine, change color or dim every 1s

8) Active current is measured with: module enabled, MCLK=32 MHz, time-out mode; WLB = 0, WUB = 0x00008000; WDT serviced every 1s

9) Active current is measured with: module enabled, MCLK=32 MHz, Periodic interrupt enabled

3.3.3 Power-Up and Supply Threshold Characteristics

Table 20 provides the characteristics of the supply threshold in XMC1200.

Table 20 Power-Up and Supply Threshold Parameters (Operating Conditions apply) ¹⁾

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
V_{DDP} ramp-up time	t_{RAMPUP} SR	$V_{DDP}/S_{VDDPrise}$	–	10^7	μs	
V_{DDP} slew rate	S_{VDDPOP} SR	0	–	0.1	V/ μs	Slope during normal operation
	S_{VDDP10} SR	0	–	10	V/ μs	Slope during fast transient within +/- 10% of V_{DDP}
	$S_{VDDPrise}$ SR	0	–	10	V/ μs	Slope during power-on or restart after brownout event
	$S_{VDDPfall}$ ²⁾ SR	0	–	0.25	V/ μs	Slope during supply falling out of the +/-10% limits ³⁾
V_{DDP} prewarning voltage	V_{DDPPW} CC	2.1	2.25	2.4	V	ANAVDEL.VDEL_SELECT = 00 _B
		2.85	3	3.15	V	ANAVDEL.VDEL_SELECT = 01 _B
		4.2	4.4	4.6	V	ANAVDEL.VDEL_SELECT = 10 _B
V_{DDP} brownout reset voltage	V_{DDPBO} CC	1.55	1.62	1.75	V	calibrated, before user code starts running
Start-up time from power-on reset	t_{SSW} SR	–	320	–	μs	Time to the first user code instruction ⁴⁾

1) Not all parameters are 100% tested, but are verified by design/characterisation.

2) A capacitor of at least 100 nF has to be added between V_{DDP} and V_{SSP} to fulfill the requirement as stated for this parameter.

Electrical Parameter

- 3) Valid for a 100 nF buffer capacitor connected to supply pin where current from capacitor is forwarded only to the chip. A larger capacitor value has to be chosen if the power source sink a current.
- 4) This values does not include the ramp-up time. During startup firmware execution, MCLK is running at 32 MHz and the clocks to peripheral as specified in register CGATSTAT0 are gated.

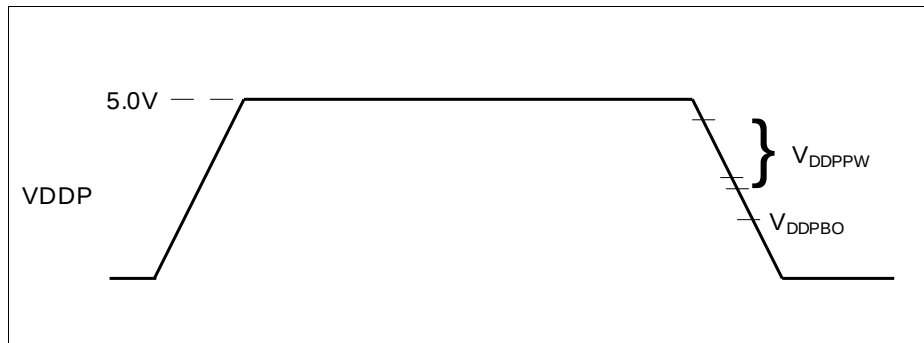


Figure 14 Supply Threshold Parameters

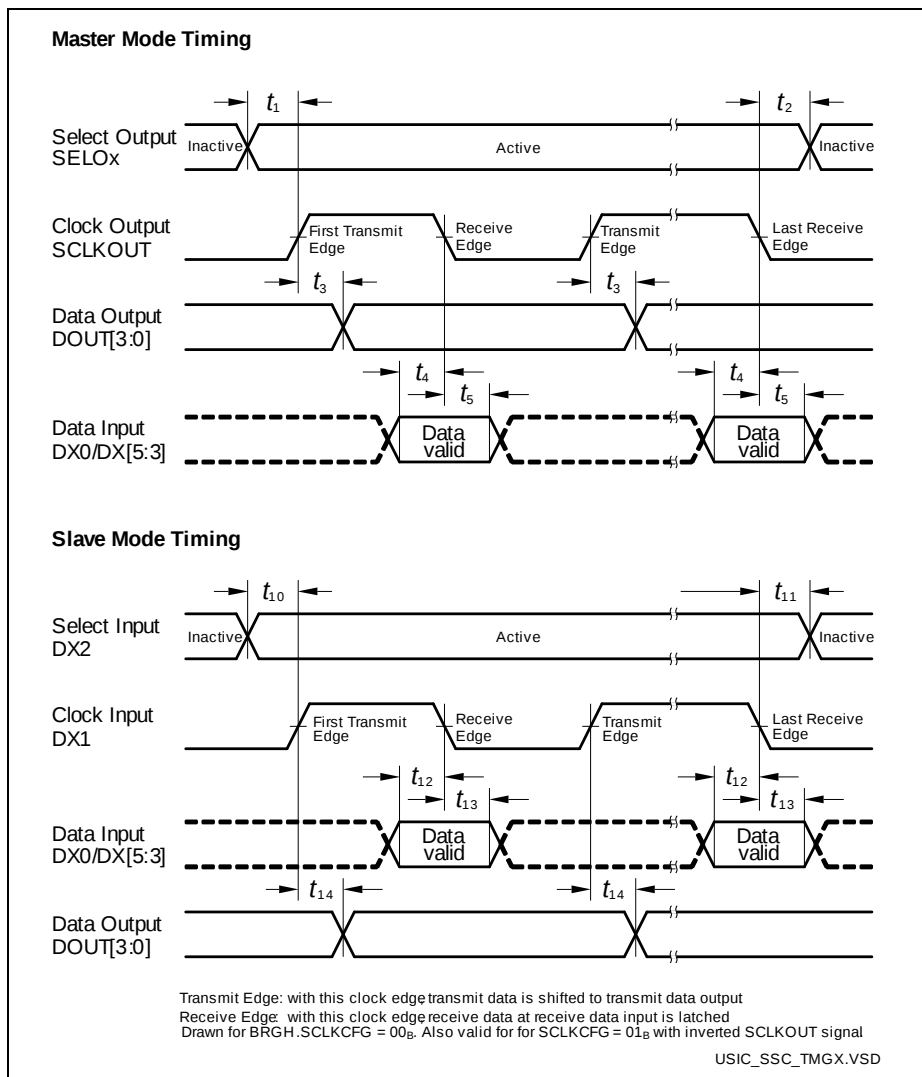


Figure 17 USIC - SSC Master/Slave Mode Timing

Note: This timing diagram shows a standard configuration, for which the slave select signal is low-active, and the serial clock signal is not shifted and not inverted.

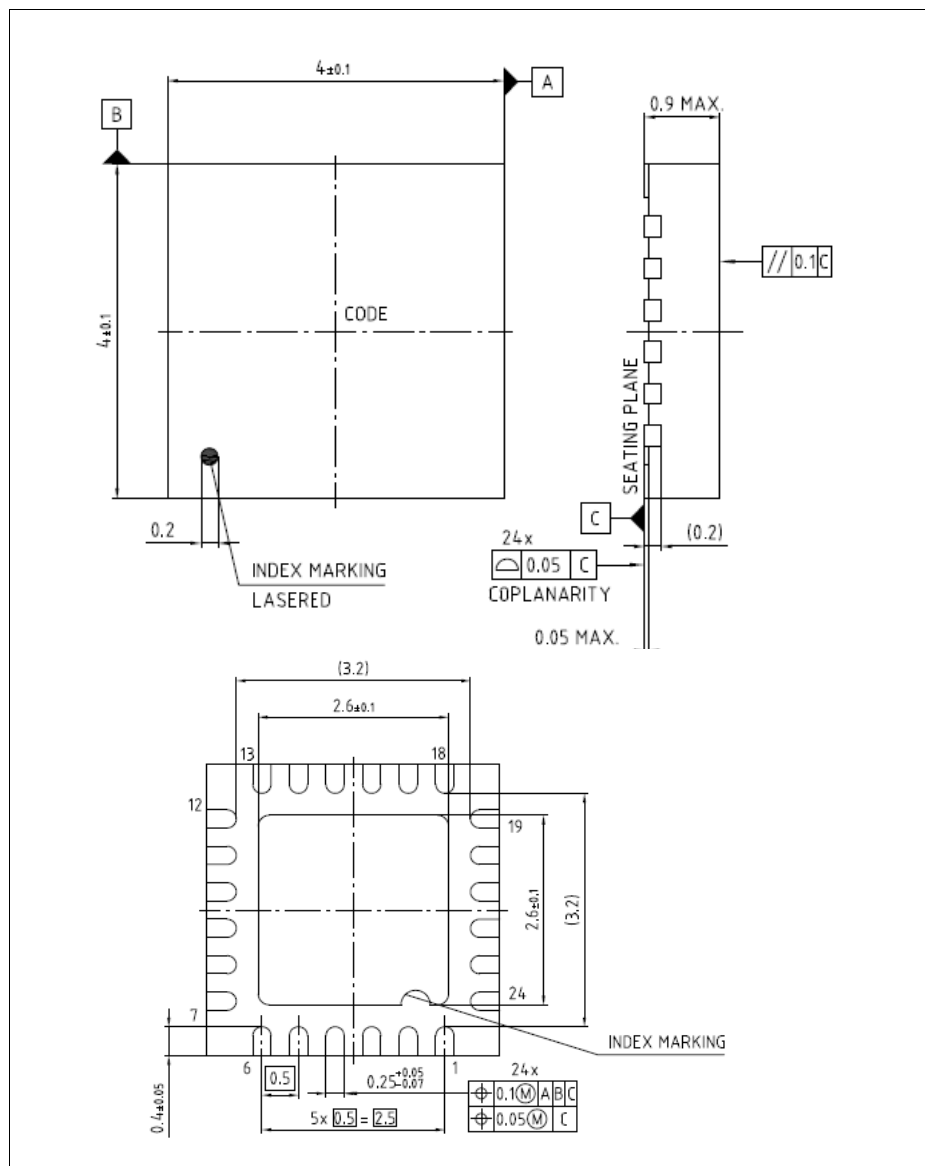


Figure 24 PG-VQFN-24-19

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